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Performance of small pore microchannel plates

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1.0 ABSTRACT

Small pore size microchannel plates (MCP's) are needed to satisfy the requirements for future high resolution small and large format detectors for astronomy. MCP's with pore sizes in the range 5 μ m to 8 μ m are now being manufactured, but they are of limited availability and are of small size. We have obtained sets of Galileo 8 μ m and 6.5 μ m MCP's, and Philips 6 μ m and 7 μ m pore MCP's, and compared them to our larger pore MCP Z stacks. We have tested back to back MCP stacks of four of these MCP's and achieved gains >2x10⁷ with pulse height distributions of <40% FWHM, and background rates of <0.3 events sec⁻¹ cm⁻². Local counting rates up to ≈100 events/pore/sec have been attained with little drop of the MCP gain. The bare MCP quantum efficiencies are somewhat lower than those expected, however. Flat field images are characterized by an absence of MCP fixed pattern noise.

Keywords: microchannel plate, UV, spectroscopy

2.0 SMALL PORE MICROCHANNEL PLATES

High spatial resolution (<15 μ m) is essential for future high resolution imaging and spectroscopy applications (FUSE)¹. Currently, the size of the MCP pores is a significant limiting issue. Our current delay line readouts have resolutions of <15 μ m FWHM and <1 μ m electronic binning (Fig 1), and we can observe² the pore position "quantization" effects for MCP's with the standard pore sizes of 10 μ m (12 μ m center-center).

A number of small pore (6μ m to 8μ m) MCP's were obtained from two manufacturers, and these are described in Table I. In each case, except for the 8μ m MCP's, the MCP's were used in a back to back stack of 4 MCP's. This was done to ensure high saturated gain and tight pulse height distribution necessary for high resolution imaging detector systems. The 8μ m MCP's were used in a Z stack configuration.

	Table I. Unital port 1202 of				
Pore size	MCP size	L:D ratio	Resistance	Bias angle	Manufacturer
611m	25mm	55:1	≈35MΩ	6°	Philips
<u>6 5μm</u>	33mm	50:1	≈60MΩ	12°	Galileo
-0.5μm	25mm	50:1	≈100MΩ	6°	Philips
7μm	251111	80.1	≈90MΩ	12°	Galileo
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Table I. Small pore MCP specifications

The MCP's were mounted in a brazed metal-ceramic detector body with a circumferential spring clamping arrangement for the MCP stack. The detector scheme is functionally similar to other devices that we have implemented in various space programs. The incoming UV photons are detected by the MCP channel walls, ejecting photoelectrons which impact the walls of MCP pores causing a charge avalanche with an overall charge multiplication of $\approx >10^7$. The field of view (18mm for the 25mm MCP's, and 25mm for the 33mm MCP's) is defined by an output aperture mask placed under the MCP stack. The brazed detector body is attached to a vacuum flange, that also has electrical feedthroughs to which the wedge and strip readout anode is mounted with a ≈ 10 mm MCP to anode gap.

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Figure 2. Optical image of a Galileo 8µm pore MCP with a 1952 air force test mask in contact

MCP with a 1952 air force test mask in contact

Figure 3. Optical image of a Philips $7\mu m$ pore MCP with a 1952 air force test mask in contact



MCP with a 1952 air force test mask in contact

SPIE Vol. 2808 / 99

2

To evaluate the limiting resolution of small pores we have also microscopically examined the small pore MCP's with a visible light back illumination through an Air Force resolution test mask (Figs. 2 to 5). As the size of the MCP pores reduces, the finer a resolution pattern can be resolved. $8\mu m$ MCP's can just resolve the 28 lp/mm pattern, but the $6\mu m$ MCP's can resolve the 40 lp/mm pattern. Small pore MCP's will hopefully eventually support a wide range of future instruments, providing better resolution performance and reducing the effects of MCP fixed pattern noise for critical applications such as high resolution spectroscopy.

3.0 MICROCHANNEL PLATE PERFORMANCE

3.1 Microchannel plate gain, pulse height distribution

The small pore 4 MCP stacks were generally tested under conditions where the entire field of view was uniformly illuminated with 2537Å light (Hg vapor lamp). The results of these tests show variations in performance from stackup to stackup, and often these differences have been due to gaps between the MCP's caused by individual MCP warpage. We have in some cases restacked the MCP's a number of times to ensure that there are no gain variations across the field of view. The pulse height spectra are gaussian in shape, demonstrating gain saturation. The gain and pulse height results for the Philips 7 μ m MCP's are shown in Figures 6 and 7. Gain of >2 x 10⁷ is achievable, which is not surprising given a four MCP's tack. The pulse height distributions (PHD's) were quite good (=40% FWHM), as indicated by the narrow distributions in Figures 6 and 7. The 4 MCP stacks of low L/D MCP's have fairly tight PHD's advantage for the discrimination of background events and reduction of the dynamic range necessary for imaging electronics. Using a beam of 256Å radiation covering about 15% of the field of view, PHD is not

The Galileo 6.5µm 4 MCP stack was more difficult to stack to obtain a tight PHD. The gain is not fully saturated at 2 x 10⁷, and gains in excess of 3 x 10⁷ were reached (Fig. 8) with pulse height distributions of ≈85% FWHM (Fig. 9). There was always a slightly higher gain in the center of the field of view, indicating slight MCP warpage. With all the small pore MCP stacks this is a potential problem since the solid edges are slightly thicker than the active pore area. The Philips 6µm pore MCP stack did not perform quite as well as the 7µm MCP's. The gains reached were again very high (>3 x 10⁷) (Fig. 10), and the PHD's were always between 55% and 50% FWHM (Fig. 11).

3.2 Background rate

The background rate and spatial distribution was assessed for each MCP type. Since the MCP field of view was open to the vacuum tank for all these tests there is a slight contribution due to stray ions in the tank. This is visible as a small "bump" in the background PHD on the background vs threshold plots. The spatial distribution for a 2200 sec integration of background events for the 7µm pore Philips MCP stack is shown in Figure 12. As expected from 40 K β decay in the glass, the distribution is essentially uniform. We observe a negative exponential pulse height distribution for background events with <0.35 events cm⁻² sec⁻¹ for a threshold of $\approx 10\%$ of the modal gain (Fig. 13). The overall background rate is =0.23 events $cm^{-2} sec^{-1}$ when the PHD peak due to tank ions is subtracted. This is lower then the rate (≈ 0.5 events cm⁻² sec⁻¹) for intrinsic β decay MCP noise^{3,4} for ⁴⁰K in the Philips glass in Z stack 80:1 MCP configurations. Since the 7 μ m MCP's are much thinner, there is less glass and hence less β decay MCP noise contributing to the intrinsic background rate. The 4 MCP 6µm Philips stack has a similar background rate behavior (Fig. 14). Again, if the tank noise peak is removed we get a rate of ≈0.27 events cm⁻² sec⁻¹ which is similar to the 7 μ m MCP performance. Thus one advantage of smaller pore MCP's is a reduced background rate at the same gain level, when compared to larger pore MCP's. The Galileo 6.5µm MCP's had a background rate of ≈ 0.53 events cm⁻² sec⁻¹ for a threshold of $\approx 25\%$ the modal gain (Fig. 15). The Galileo MCP's had a higher incidence of low amplitude hot spots for these



Figure 6. Pulse height distributions for a 4 MCP stack of Philips 7µm pore 50:1 L/D MCP's.



Gain Figure 8. Pulse height distributions for a 4 MCP stack of Galileo 6.5µm pore 50:1 L/D MCP's.















stack of Philips 6µm pore 55:1 L/D MCP's.

SPIE Vol. 2808 / 101

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Figure 12. Background event image for a 4 MCP stack of Philips 7µm pore 50:1 L/D MCP's.

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Figure 13. Background event rate for a 4 MCP stack of Philips 7µm pore 50:1 L/D MCP's.

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particular MCP's, which increased the rate at small thresholds. The overall rate of ≈ 0.53 events cm⁻² sec⁻¹ is about a factor of two higher than the standard Philips glass because ⁸⁷Rb is present rather than ⁴⁰K. The background rates for standard Philips (12µm) and Galileo (10µm) 80:1 Z stacks is shown in Fig.16. These are compared with an early batch of low noise Galileo 10µm MCP's with and without lead shielding. A recent result with new Galileo low noise glass is also included. These are 95 x 20mm curved surface MCP's in a Z stack of 3 x 80:1 MCP's for the FUSE explorer satellite. This result is very encouraging, with rates of <0.04 events cm⁻² sec⁻¹ at ≈20% modal gain threshold (without lead shielding). If small pore MCP's can be made from this material we expect very low intrinsic background rates (<0.02 events cm⁻² sec⁻¹).

3.3 Counting rate performance

At high local event rates there is a progressive drop in the MCP stack gain and a degradation of the pulse amplitude distribution^{5,6,7} due to the finite response time of MCP channel(s). The counting rate limit is proportional to the resistance of the MCP's, and is also dependent on the area illuminated. Only the Philips 6µm MCP's were low in resistance, so these were chosen for rate dependence tests. The 6µm MCP's have resistance in the range $170M\Omega/cm^2$ ($\approx 35M\Omega$ per MCP), which is slightly less than the MCP's used for the SOHO satellite⁸. Tests were made to evaluate the response to high local counting rate conditions such as those in some astronomical spectroscopy and imaging experiments. The high local counting rates on the MCP were generated using a variable flux from a pen ray lamp to illuminate a pinhole mask with 10µm 25µm, 50µm and 75µm pinholes. The gain as a function of local counting rate for the Philips 6µm 4 MCP stack is shown in Figure 17. The results show that the MCP gain remains stable up to ≈ 100 events pixel⁻¹ sec⁻¹ for the 10µm and 25µm pinholes. So for this size input function the high local rates cause no loss of events or resolution degradation. For the 50µm holes the gain drop is $\approx 30\%$ at ≈ 100 events pore⁻¹ sec⁻¹, and the gain drop is $\approx 70\%$ at ≈ 100 events pore⁻¹ sec⁻¹ for the 75µm pinholes. The PHD behavior (Fig. 18) for the 10µm and 25µm pinholes is essentially independent of the counting rate, with only a hint of broadening at ≈ 100 events pore⁻¹ sec⁻¹. Both the 50µm holes and the 75µm pinholes show significant PHD broadening at the higher counting rates. The 75µm pinhole PHD's begin to broaden at even a few counts pore⁻¹ sec⁻¹. These effects are essentially in accord with earlier observations of the dependence on the illuminated area⁷. One must also appreciate that a large number of pores are affected at the output MCP of the stack, and it is here where the charge extraction is largest and limitation occurs. It is also important to note that, for example, the counting rate in the 25µm pinhole at 100 events pore⁻¹ sec⁻¹ is over 1000 events sec⁻¹, which is a significantly high rate.

3.4 Quantum detection efficiency

The quantum detection efficiency (QDE) of the bare 6 μ m, 6.5 μ m, 7 μ m and 8 μ m MCPs were measured as part of the overall characterization. The QDE vs wavelength properties were measured in an ultra high vacuum chamber at $\approx 10^{-6}$ torr with the MCP detector mounted such that the incident angle was $\approx 13^{\circ}$ to the MCP pore axis. Monochromatic radiation was provided by a gas discharge hollow cathode source in combination with a 1m grazing incidence monochromator. After corrections are made for the contribution of the background radiation the absolute QDE's are derived from flux measurement comparisons with a reference standard. The choice of reference standard depends on wavelength - measured; a NIST ultraviolet windowless photodiode, or a NIST far ultraviolet windowed photodiode were employed. The accuracy of the absolute QDE measured is determined largely by the accuracy of the reference standards. The NIST EUV photodiode has a most probable error of 10% from 68Å to 1216Å and the NIST far ultraviolet photodiode has a most probable error of 10% from 1216Å to 2537Å.

The results presented in Figure 19 show that the efficiencies for the Philips MCP's are slightly lower than expected compared to other bare MCP data⁹ which we consider more "normal". The same kind of problem was also apparent (Fig. 20), although less severe, for the Galileo MCP's. The open area ratio of



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Figure 17. Gain vs counting rate & spot area for a 4 MCP stack of Philips 6µm pore MCP's



Figure 19. QDE of $6\mu m$ and $7\mu m$ pore Philips MCP's as a function of wavelength.

Figure 18. Gain vs counting rate & spot area for a 4 MCP stack of Philips 6µm pore MCP's



Figure 20. QDE of $6.5\mu m$ and $8\mu m$ pore Galileo MCP's as a function of wavelength.



Figure 21. Flat field image for a 4 MCP stack of Philips $6\mu m$ pore MCP's.



Position (mm) Figure 23. Flat field image histogram slice for a 4 MCP stack of Philips 6μm pore MCP's.





Figure 22. Flat field image for a 4 MCP stack of Philips $7\mu m$ pore MCP's.



0 5 10 15 20 Position (mm) Figure 24. Flat field image histogram slice for a 4 MCP stack of Philips 7μm pore MCP's.



SPIE Vol. 2808 / 105

the small pore MCP's is 60% to 65% for all the MCP's, compared with \approx 65% for normal 10µm and 12.5µm pore MCP's. Therefore there are no obvious changes in the open area ratio and this does not seem to be an issue. Over the past few years we have noticed on a number of occasions that the QDE of some batches of MCP's that the QDE was significantly below that expected. After a considerable amount of study we have established that the actual QDE of the photoemitting surfaces is probably not degraded. We surmise that problem is possibly due to inefficient detection of the emitted photoelectrons by the MCP (electron detection probability in Ref 10). We are currently attempting to resolve this problem with the manufacturers and will report on this at a future date.

3.5 Flat field characteristics

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Deep flat field images (>1000 events/pixel) for the 6µm and 7µm MCP stacks were obtained under illumination with 2537Å light (Hg vapor lamp). The contrast enhanced flat field response of the 6µm and 7µm MCP stacks are shown in Figures 21 and 22 respectively. Flat field images were acquired at rates of ≈10,000 events/sec, and binned into a 128x128, 125µm bin format. The only visible flat field modulation effects are the edge intensity enhancements due to reflections of light by the detector clamps. Typically the dominating modulation seen in flat field images is that of the MCP multifibers. MCP modulation at the multifiber boundaries is usually of the order 10%-15%¹¹. It is unusual that these MCP's do not show the MCP multifiber structure. Earlier results have linked the MCP multifiber modulation to physical distortions of the MCP pores at the boundaries of the multifibers¹¹.

Histograms of the intensity maps for the images in Figures 21 and 22 are shown in Figs. 23 and 24 respectively. The intensity variations in the central areas are small and have no scale length pattern correlations. The statistical variations of the flat field intensity in the central 5mm of the images are shown in Figures 25 and 26. The expected variations are 6.5% and 6.9% FWHM for the 6 μ m and 7 μ m flat fields respectively. The measured values are very close to those expected, which also confirms that there is little multifiber modulation.

4.0 ACKNOWLEDGMENTS

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